FINAL DRAFT
International Standard

ISO/FDIS 11452-3

Road vehicles — Component test methods for electrical disturbances from narrowband radiated electromagnetic energy —

Part 3: Transverse electromagnetic (TEM) cell

Véhicules routiers — Méthodes d'essai d'un équipement soumis à des perturbations électriques par rayonnement d'énergie électromagnétique en bande étroite —

Partie 3: Cellule électromagnétique transverse (TEM)

ISO/TC **22**/SC **32**

Secretariat: **JISC**

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Contents

Page

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Document Preview
ISO/FDIS 11452-3
https://standards.iteh.ai/catalog/standards/iso/64ae42e2-d5c4-49dd-a0b2-d081ef66b8de/iso-fdis-11452-3

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Foreword

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This document was prepared by Technical Committee ISO/TC 22, *Road vehicles*, Subcommittee SC 32, *Electrical and electronic components and general system aspects*.

This fourth edition cancels and replaces the third edition (ISO 11452-3:2016), of which it constitutes a minor revision. The changes are as follows:

— Formula (1) in 6.6.2 was modified.

A list of all parts in the ISO 11452 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

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Introduction

Immunity measurements of complete road vehicles are generally able to be carried out only by the vehicle manufacturer, owing to, for example, high costs of absorber-lined shielded enclosures, the desire to preserve the secrecy of prototypes or a large number of different vehicle models.

For research, development and quality control, a laboratory measuring method can be used by both vehicle manufacturers and equipment suppliers to test electronic components.

The TEM cell method has the major advantage of not radiating energy into the surrounding environment. The method can be used for testing either the immunity of a component with the field coupling to the wiring harness or the immunity of the component alone with minimum exposure to the wiring harness.

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Road vehicles — Component test methods for electrical disturbances from narrowband radiated electromagnetic energy —

Part 3: Transverse electromagnetic (TEM) cell

1 Scope

This document specifies transverse electromagnetic (TEM) cell tests for determining the immunity of electronic components of passenger cars and commercial vehicles to electrical disturbances from narrowband radiated electromagnetic energy, regardless of the vehicle propulsion system (e.g. spark-ignition engine, diesel engine, electric motor).

The electromagnetic disturbances considered are limited to continuous narrowband electromagnetic fields.

2 Normative references

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The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 11452-1, *Road vehicles — Component test methods for electrical disturbances from narrowband radiated electromagnetic energy — Part 1: General principles and terminology*

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3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 11452-1 apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

— ISO Online browsing platform: available at https://www.iso.org/obp

— IEC Electropedia: available at https://www.electropedia.org/

4 Test conditions

The upper frequency range limit of the TEM cell is a direct function of the TEM cell dimensions.

For testing automotive electronic systems, a 0,01 MHz to 200 MHz TEM cell should be used. See Annex A for suggested cell dimensions. See Annex B for methods to determine TEM-cell frequency range.

The user shall specify the test severity level or levels over the frequency range. See Annex E for suggested test severity levels.

Standard test conditions shall be those given in ISO 11452-1 for:

— test temperature;

— supply voltage;

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— modulation;

— dwell time;

— frequency step sizes;

— definition of test severity levels;

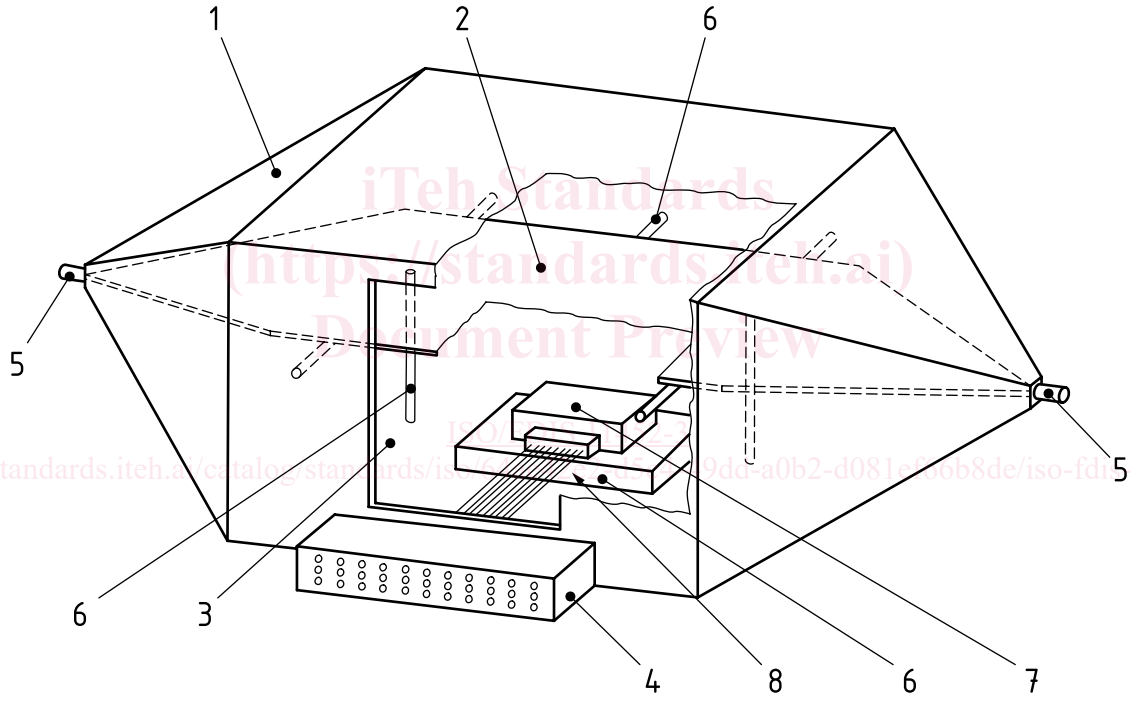
— test-signal quality.

5 Test apparatus

5.1 TEM cell

The TEM cell used for this test is a rectangular coaxial line with a 50 Ω characteristic impedance (see Figure 1). The device under test is exposed to a uniform TEM field.

The TEM cell is a laboratory measurement system which can be used to generate test fields within 2 dB of the theoretical value if the device under test does not occupy an excessive portion of the test volume (see 5.3).



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Key

1 outer conductor (shield)
2 septum (inner conductor)
3 access door
4 connector panel (optional)
5 coaxial connectors
6 dielectric support (relative permittivity $\varepsilon_r \leq 1{,}4$)
7 device under test
8 input/output leads

Figure 1 — TEM cell

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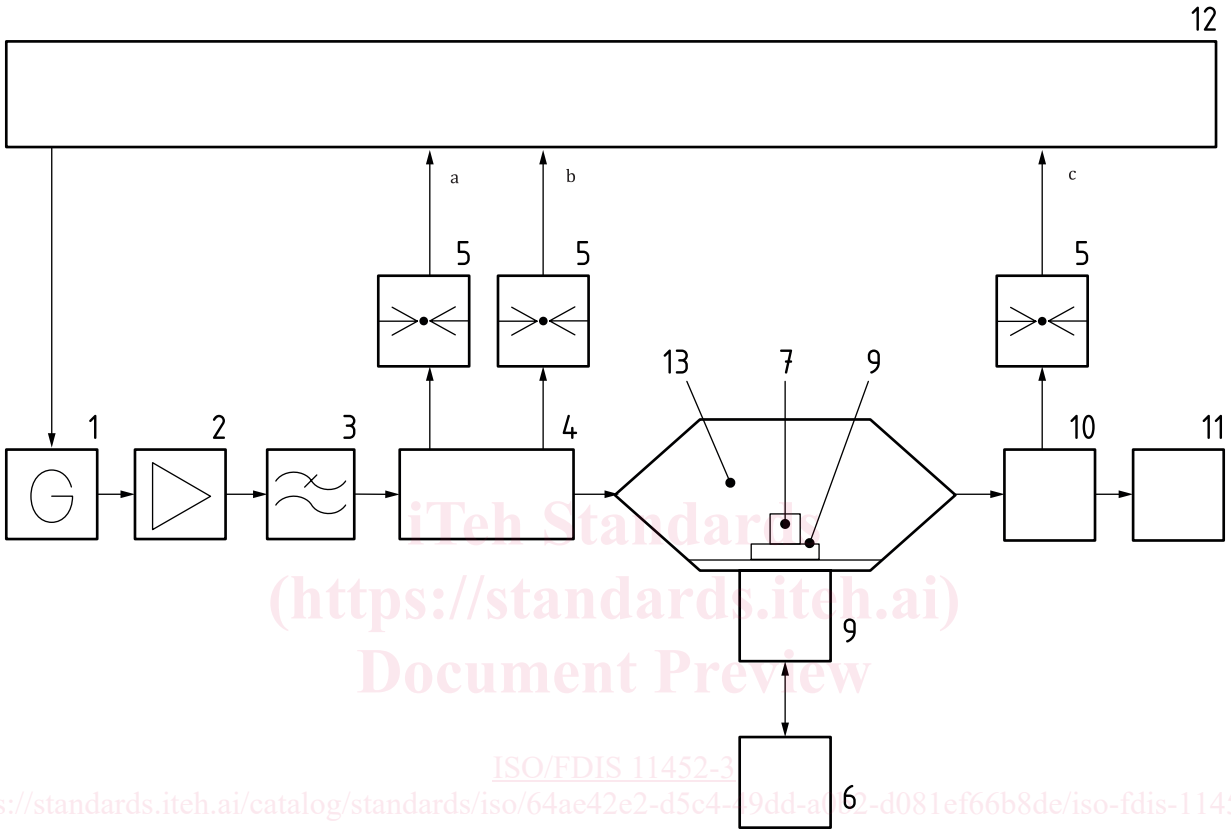
5.2 Instrumentation

Figure 2 shows an example of a TEM cell test set-up. The TEM cell has high resonances in the region greater than the recommended upper frequency limit.

A low pass filter with an attenuation of at least 60 dB at frequencies above 1,5 times the cut-off frequency of the TEM cell may be installed (e.g. 200 MHz TEM cell: 60 dB for frequencies above 300 MHz) to avoid resonances.

Example of installation of low pass filter is given in Annex C.



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Document Preview
ISO/FDIS 11452-3
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Key

1	signal generator	9	low pass filters/connector panel
2	broadband amplifier	10	coupler
3	low pass filter (optional)	11	high power load (50 Ω)
4	dual-directional coupler (30 dB decoupling ratio minimum)	12	controller
		13	TEM cell
5	RF-power meter	a	$P_{forward}$ (forward power).
6	peripheral	b	$P_{reflected}$ (reflected power).
7	device under test	c	P_{output} (output power).
8	dielectric support		

Figure 2 — Example TEM cell configuration

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5.3 Test set-up

5.3.1 General

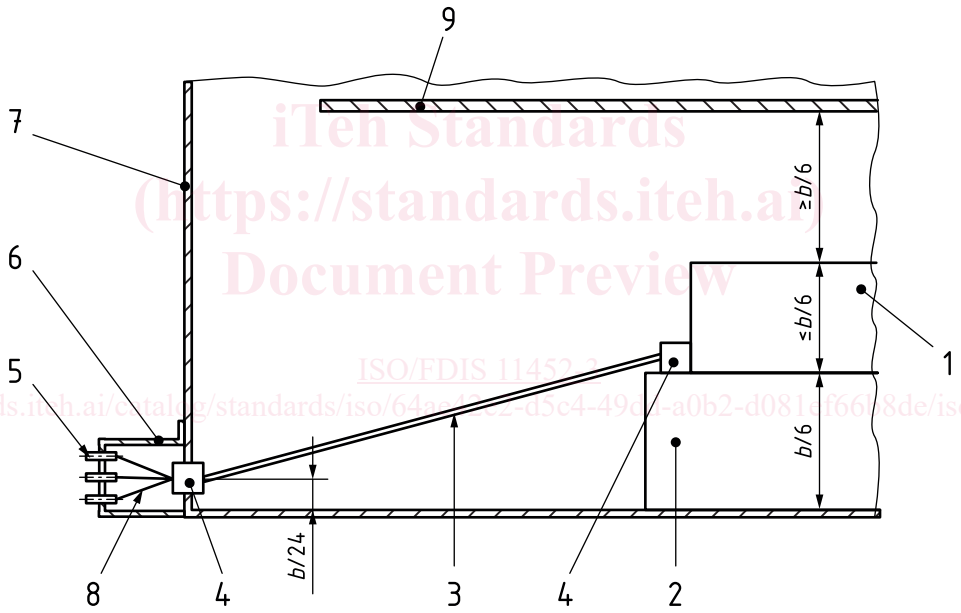
In order to maintain the homogeneous field in the TEM cell and obtain reproducible measurement results, the device under test shall be no larger than one-sixth of the cell (inside) height *b* (see Figure 3 and Figure A.1). The device under test should be placed in the centre of the cell on a dielectric equipment support.

The device under test and the wiring harness may be positioned in either of two arrangements, depending on whether the exposure of the device under test and the wiring harness (see 5.3.2) or that of the device alone (see 5.3.3) is being tested.

An alternative test set-up without low pass filter is presented in Annex D.

5.3.2 Exposure of device under test and wiring harness (for major field coupling to the harness)

The height of the dielectric support is one-sixth of cell height *b* (see Figure 3). In order to obtain reproducible measurement results, the device under test, together with its wiring harness or printed circuit board, shall be placed in the same position in the TEM cell for each measurement. In addition to the direct RF-field coupling to the device under test, the use of an unshielded harness or printed circuit board will result in a common mode electrical field coupling and a differential mode magnetic field coupling, depending on the inclination and the width of the harness or circuit board.



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Key

1 device under test
2 dielectric support (relative permittivity $\varepsilon_r \leq 1{,}4$)
3 printed circuit board (no ground plane) or wiring harness, unshielded
4 connector
5 coaxial connectors
6 connector panel
7 TEM cell wall
8 cables
9 septum
b TEM cell height (see Annex A)

Figure 3 — Example test set-up — Major field coupling to wiring harness (side view)

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